

TESIS

**PERHITUNGAN KONSTANTA DIELEKTRIK GRAPHENE
NANOSTRUCTURED PADA SUBSTRAT SiC DAN SiO₂/Si HASIL
PENGUKURAN *SPECTROSCOPY ELLIPSOMETRY* MENGGUNAKAN
METODE INVERSI NEWTON-RAPHSON**

**CALCULATION OF DIELECTRIC CONSTANT OF NANOSTRUCTURED
GRAPHENE ON SiC AND SiO₂/Si SUBSTRATE OF *SPECTROSCOPY
ELLIPSOMETRY* MEASUREMENT RESULTS USING NEWTON-
RAPHSON INVERSION METHOD**



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